

# SEMICONDUCTOR TECHNICAL DATA

# KID65783AP/AF

### BIPOLAR LINEAR INTEGRATED CIRCUIT

### 8CH HIGH-VOLTAGE SOURCE DRIVER

The KID65783AP/AF is comprised of eight source current transistor array. This driver is specifically designed for fluorescent display applications. Applications include relay, hammer and lamp drivers.

#### **FEATURES**

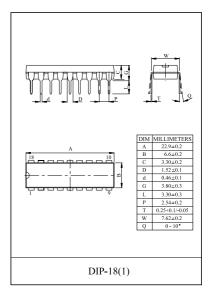
- $\cdot$  High Output Voltage : V<sub>CC</sub>=50V(Min.).
- · Output Current (Single Output) I<sub>OUT</sub>: -500mA(Min.).
- · Output Clamp Diodes.
- · Single Supply Voltage.
- $\cdot$  Input Compatible With Various Types of Logic.
- · Package Type-AP: DIP-18pin. DIP-18(1)Pin
- · Package Type AF: FLP-20pin.

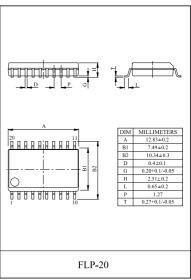
TYPE	DESIGNATION
KID65783AP/AF	TTL, 5V CMOS

### MAXIMUM RATINGS (Ta=25 )

CHARACTERISTIC		SYMBOL	RATING	UNIT	
Supply Voltage		$V_{CC}$	50	V	
Output Current		I <sub>OUT</sub>	-500	mA/ch	
Input Voltage		V <sub>IN</sub>	15	V	
Clamp Diode Reverse Voltage		$V_R$	50	V	
Clamp Diode Forward Current		$I_F$	500	mA	
Power Dissipation	AP	P <sub>D</sub> (Note)	1.47	W	
	AF	I D (Note)	0.96	, vv	
Operating Temperature		$T_{opr}$	-40 85		
Storage Temperature		$T_{stg}$	-55 150		

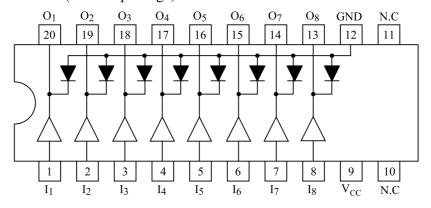
Note) Delated above 25  $\,$  in the proportion of 11.7W/ (AP Type), 7.7W/ (AF Type).



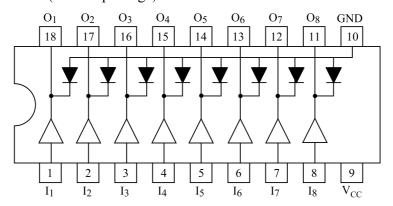


# PIN CONNECION (TOP VIEW)

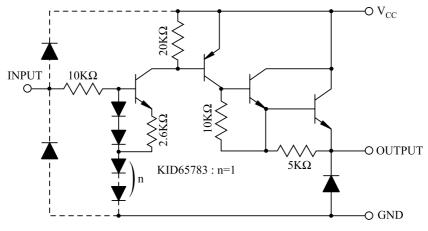
AF-TYPE (FLP-20 package)



### AP-TYPE (DIP-18 package)



### **SCHEMATICS (EACH DRIVER)**



(Note) The input and output parasitic diodes cannot be used as clamp diodes.

### RECOMMENDED OPERATING CONDITIONS (Ta=-40 85 )

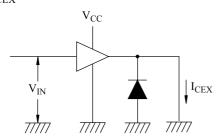
CHARACTERISTIC		SYMBOL	TEST CONDITION		MIN.	TYP.	MAX.	UNIT	
Supply Voltage		V <sub>CC</sub>	-		-	-	50	V	
Output Current			Ta=85 Tj=120	Duty=10% 8 Circuits	-	-	-260		
	AP	${ m I_{OUT}}$		Duty=50% 8 Circuits	-	-	-59 mA/c	mA/ch	
		1001		Tpw=25mS	Duty=10% 8 Circuits	-	-	-180	m/A/Cn
	AF		Duty=50% 8 Circuits	-	-	-38			
Input Voltage		$V_{IN}$	-		-	-	12	V	
Input Voltage	Output ON	V <sub>IN (ON)</sub>	-		2.0	5.0	15	v	
	Output OFF	V <sub>IN (OFF)</sub>	-		0	-	0.8	v	
Clamp Diode	AP	$V_R$	V		-	-	50	v	
Reverse Voltage	AF		-		-	-	35	<b>v</b>	
Clamp Diode Forward Current		$I_{\mathrm{F}}$	-		-	-	400	mA	
Power Dissipation	AP	AP P <sub>D</sub>	-		-	-	0.52	W	
	AF				-	-	0.35	vv	

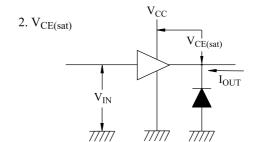
# ELECTRICAL CHARACTERISTICS (Ta=25 )

CHARACTERISTIC	SYMBOL	TEST CIRCUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Output Leakage Curret	I <sub>CEX</sub>	1	$V_{CC}=V_{CC\ MAX}$ . $V_{IN}=0.4V$ Ta=25	-	-	100	μA
Output Saturation Voltage	V <sub>CE(sat)</sub>	2	V <sub>IN</sub> =V <sub>IN(ON)</sub> , I <sub>OUT</sub> =-350mA	-	-	2.0	V
			V <sub>IN</sub> =V <sub>IN(ON)</sub> , I <sub>OUT</sub> =-225mA	-	-	1.9	
			V <sub>IN</sub> =V <sub>IN(ON)</sub> , I <sub>OUT</sub> =-100mA	-	-	1.8	
Input Current	I <sub>IN(ON)</sub>	3	V <sub>IN</sub> =2.4V	-	36	52	· μΑ
			V <sub>IN</sub> =3.85V	-	180	260	
Input Voltage	V <sub>IN(ON)</sub>	4	V <sub>CE</sub> =2.0V, I <sub>OUT</sub> =-350mA	-	-	2.0	V
	V <sub>IN(OFF)</sub>		4	Ι <sub>ΟUT</sub> =-500 μΑ	0.8	-	-
Supply Current	I <sub>CC(ON)</sub>	3	V <sub>IN</sub> =V <sub>IN(ON)</sub> , V <sub>CC</sub> =50V	-	-	2.5	mA/ch
Clamp Diode Reverse Current	$I_R$	5	V <sub>R</sub> =50V	-	-	50	μA
Clamp Diode Forward Voltage	$V_{\mathrm{F}}$	6	I <sub>F</sub> =350mA	-	-	2.0	V
Turn-On Delay	t <sub>ON</sub>	7	$V_{CC}=V_{CC\ MAX}$ . $R_L=125$	-	0.15	-	
Turn-Off Delay	t <sub>OFF</sub>		$C_L=15pF$	-	1.8	-	μs

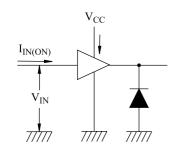
### **TEST CIRCUIT**

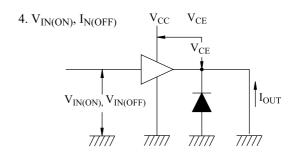
### 1. $I_{CEX}$



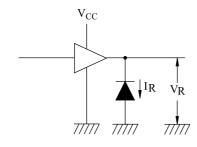


### 3. I<sub>IN(ON)</sub>, I<sub>CC</sub>

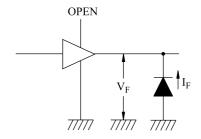




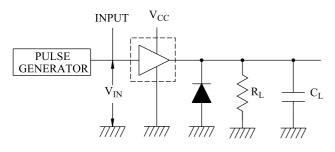
### 5. I<sub>R</sub>



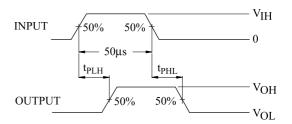




7.  $t_{ON}$ ,  $t_{OFF}$ 



 $\begin{array}{ll} \mbox{(Note 1) Pulse width } 50\mu S, \mbox{ duty cycle } 10\% \\ \mbox{Output impedance } 50\Omega \ , \mbox{ } t \leqq 5ns, \mbox{ } t \leqq 10ns \\ \mbox{(Note 2) } C_L \mbox{ includes probe and jig capacitance} \end{array}$ 



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